

**Notice of References Cited**

Application/Control No.

10/550,800

Applicant(s)/Patent Under  
Reexamination  
NAGAI ET AL.

Examiner

Jack I. Berman

Art Unit

2881

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,409,683 A	04-1995	Tillotson et al.	423/338
*	B	US-6,320,937 B1	11-2001	Mochizuki, Takayasu	378/143
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11345698 A	12-1999	Japan	KONAKAWA et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Choi et al., "Detailed space-resolved characterization of a laser-plasma soft-x-ray source at 13.5-nm wavelength with tin and its oxides", Journal of the Optical Society of America, Vol. 17, No. 9, September 2000, pages 1616-1625.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.